



7th High Level Expert Meeting 2015

Asphere Metrology On Joint Investigations

Detailed Programme

1st Day

Tuesday, 17 March 2015 / **Morning**

Chair: Gunter Schneider; Schneider GmbH & Co. KG; Germany

- 9:00 Registration
- 10:00 Conference Opening and Overview
Frank Löffler; CC UPOB e.V.; Germany
- 10:05 Review of Measurement Methods and Results
Michael Schulz; PTB; Germany
- Session – Single Point Measurement**
- 10:35 Asphere/Freeform Metrology and Round Robin Result by UA3P;
Keishi Kubo; Panasonic Production Engineering Co.,Ltd.; Japan
- 11:15 Coffee Break, Networking and Table Top Presentations
- 11:45 Asphere Measurements Using the Isara 400 CMM;
Ivo Widdershoven; IBS Precision Engineering; The Netherlands
- 12:25 Non-contact 3D form measurement of aspheres
including decenter and wedge error determination;
Gernot Berger; Luphos GmbH; Germany
- 13:05 Lunch Break, Networking and Table Top Presentations

1st Day

Tuesday, 17 March 2015 / **Afternoon**

Chair: Jean-Michel Asfour; Dioptic GmbH; Germany

- Lunch Break, Networking and Table Top Presentations
- 14:10 Non-Contact and Contact 3D Profilometry and Tilted Wave
Interferometry in Direct Comparison
Andreas Beutler; Mahr GmbH; Germany
- 14:50 **Session – Theoretical Contributions**
Measurement and Calibration Methods for Cylindrical Optics;
Jan-Peter Richters; Berliner Glas KGaA; Germany
- 15:20 Coffee Break, Networking and Table Top Presentations
- 15:50 Simulations for Optical Metrology at PTB
Ines Fortmeier; PTB; Germany
- 16:20 Measuring Position and Figure Deviation with Computer
Generated Holograms;
Matthias Beier; Fraunhofer IOF; Germany
- 16:50 Closing
- 19:00 Conference Dinner



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2nd Day Wednesday, 18 March 2015 / **Morning**

Chair: Andreas Beutler; Mahr GmbH; Germany

9:00 Opening

Session – Interferometry and CGH- Measurements

9:05 HLEM Round Robin Asphere Test 2015 at the Deggendorf Institute of Technology

Johannes Liebl;
Deggendorf Institute of Technology – Technologicampus Teisnach; Germany

9:45 Measurement Results of the Tilted-Wave-Interferometer;
Goran Baer; Institut für Technische Optik, University of Stuttgart; Germany

10:25 Coffee Break, Networking and Table Top Presentations

Session – Deflectometry / Raytracing

10:55 Requirements for Deflectometry on Aspheres;
Jan Burke; Bremer Institut für angewandte Strahltechnik GmbH; Germany

11:10 Measurement of Aspheric Surface Profiles Using Scanning Deflectometry; Iris Erichsen; Trioptics GmbH; Germany

11:50 Evaluation and Discussion of the Intercomparison
Gernot Blobel; PTB; Germany

12:30 Discussion and Outlook
Michael Schulz; PTB and Frank Löffler; CC UPOB e.V.; Germany

13:10 **Conference Closing**

Lunch and Afterwards Departure of the Guests

2nd Day Wednesday, 18 March 2015 / **Afternoon**

Lunch and Afterwards Departure of the Guests